

### **Amendments to the Drawings**

The attached Appendix includes an Annotated Marked-up Drawing of FIG. 1 and a Replacement Sheet, including FIG. 1. In FIG. 1, previously omitted element 9 has been added, as requested by the Office.

### **REMARKS**

Claims 1-3, 5-19, and 21-24 are pending in the present application. Claims 4 and 20 have been cancelled.

The specification has been amended to correct typographical errors.

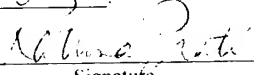
Claim 1, as amended, recites a method of exposing a target material to an ion beam in an ion implantation system comprising detecting an ion beam at a first location with a first detector, detecting the ion beam at a second location with a second detector at the same time as the first detector, quantifying an amount of ion beam neutralization based upon a measurement deviation between the first and second detectors, and controlling a characteristic of the ion beam of the implantation system based upon the amount of ion beam neutralization.

The use of two detectors taking measurements simultaneously at different locations is an improvement over the previous methodologies for determining total ion dose due to charge neutralization.

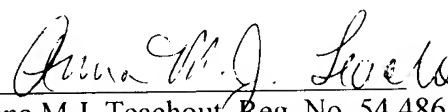
Walther provides no suggestion or motivation to implement dual detector measurements from different locations at the same time to calculate a reference ratio for determining charge neutralization. Therefore, withdrawal of the rejections of claims 1 and 19 are requested, and early notice of allowance to this effect is earnestly solicited. In addition, claims dependent from the allowable independent claims are also allowable, and provide additional points of novelty. If, for any reason, the Office is unable to allow the Application on the next Office Action, and

believes a telephone interview would be helpful, the Examiner is respectfully requested to contact the undersigned representative.

No fees are believed to be due with this Response. However, in the event it is determined any fees are due in association with this correspondence, please charge the Advanced Micro Devices, Inc. deposit account number 01-0365.

CERTIFICATE OF TRANSMISSION/MAILING	
I hereby certify that this correspondence is being facsimile transmitted to the USPTO or deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to the Commissioner for Patents on <u>8 Dec 2003</u> .	
Katrina Prati	
Typed or Printed Name	Signature

Respectfully submitted,

  
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# **APPENDIX**

to

Response to Office Action  
filed August 20, 2003  
re: U.S. App. No. 10/082,567

ANNOTATED MARKED-UP DRAWING  
REPLACEMENT SHEET

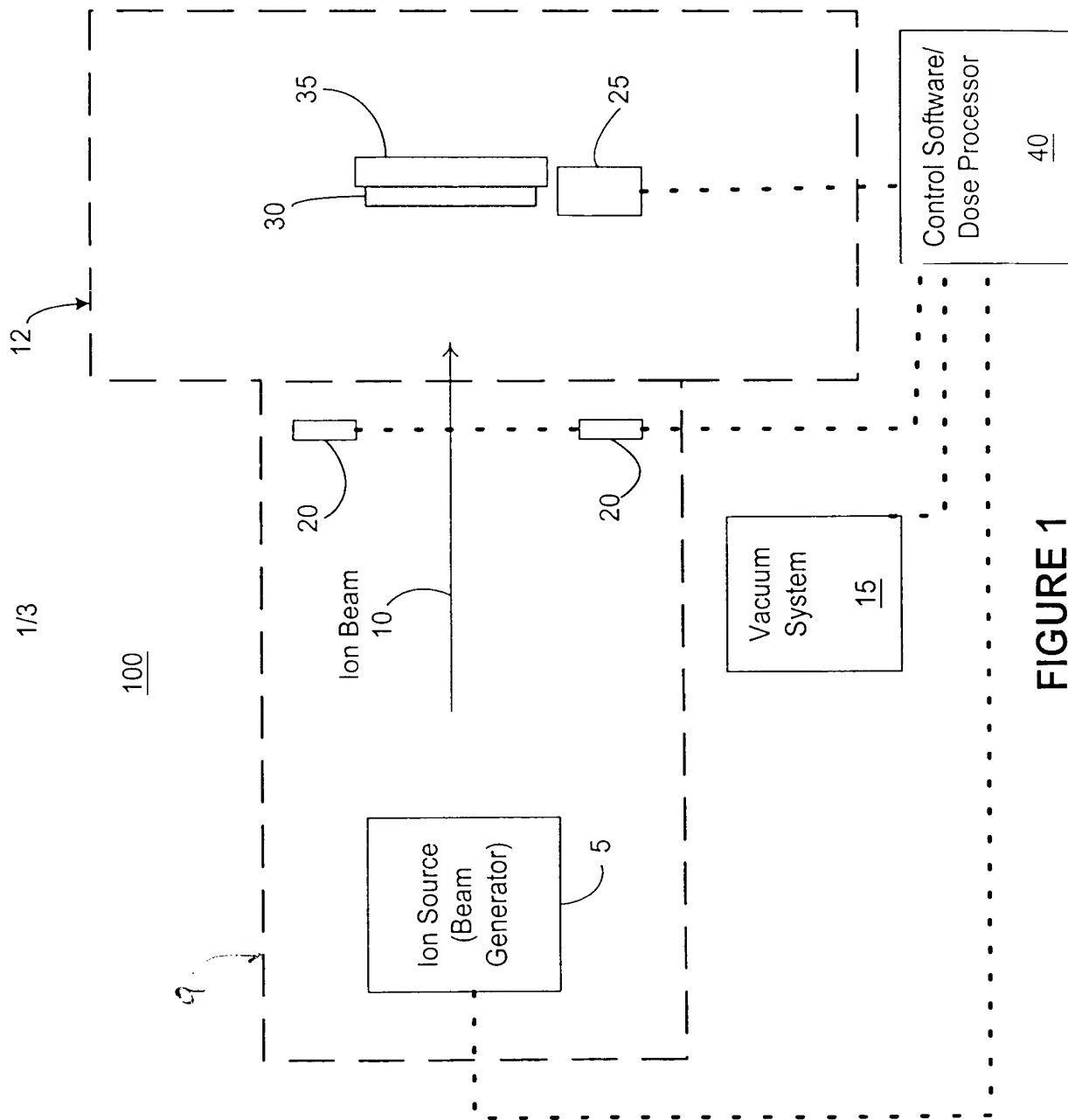
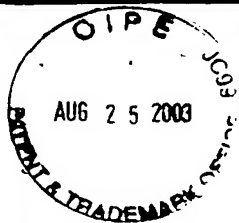


FIGURE 1



App. No.: 10/082,567  
Atty Dkt No.: 1458.TT4763  
Inventor: Tom Tse et al.  
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REPLACEMENT SHEET  
1/1

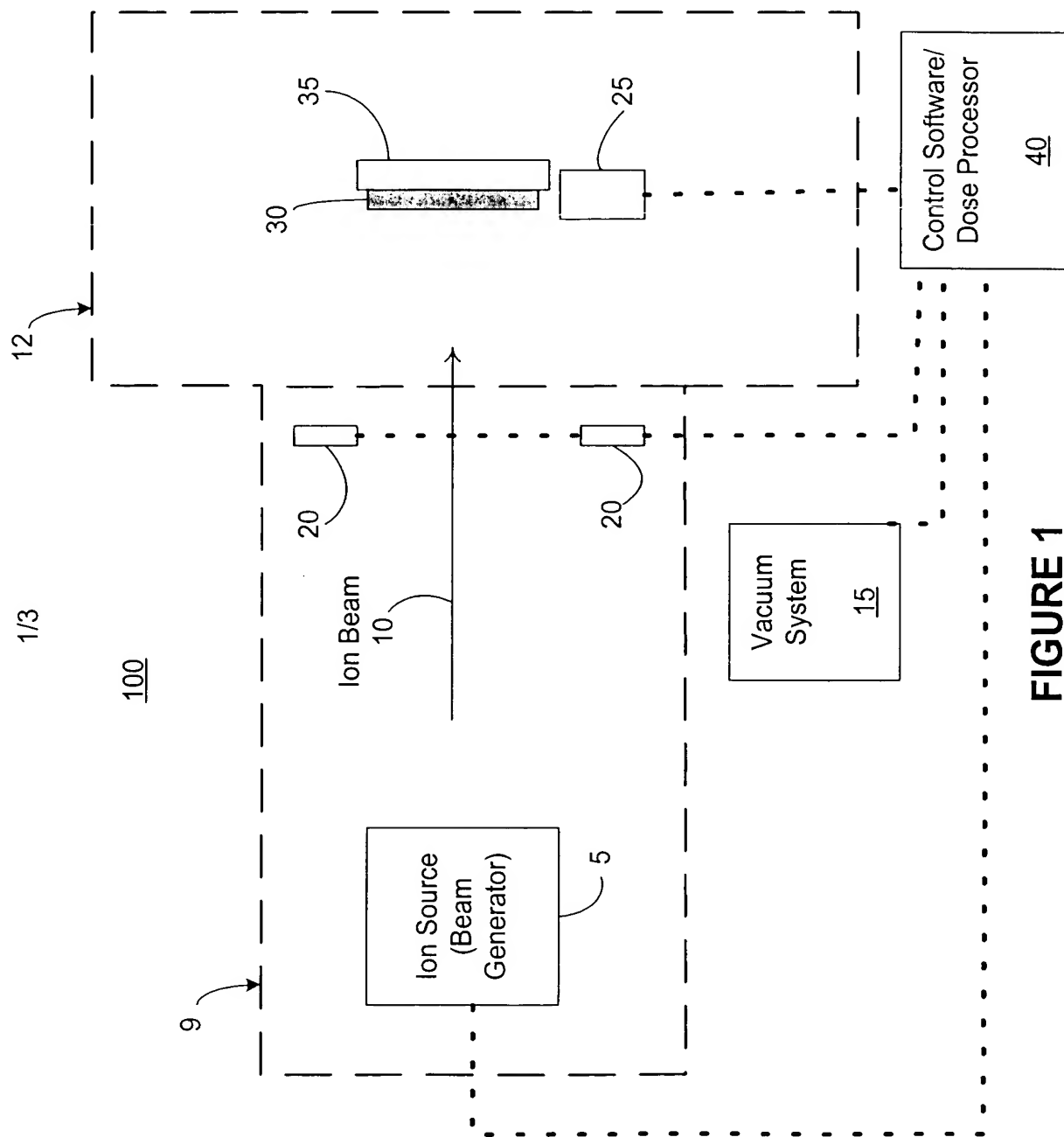


FIGURE 1